

PATENT APPLICATION

Sheet 1 of 2

FORM PTO-1449		ATTY. DOCKET NO. 200208596-1	APPLICATION NO. 10/635283	CONFIRMATION NO.
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANT Tyson R. McGuffin	FILING DATE	GROUP 2805

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
<i>BJ</i>	1A 5,880,967	03/09/1999	Jyu, et al.	
<i>PA</i>	1B 5,949,723	09/07/1999	Clemen, et al.	
<i>BJ</i>	1C 6,097,207	08/01/2000	Bernstein, et al.	
<i>BJ</i>	1D 6,209,122 B1	03/27/2001	Jyu, et al.	
<i>BS</i>	1E 6,339,835 B1	01/15/2002	Reddy, et al.	
<i>PA</i>	1F 6,513,145 B1	01/28/2003	Venkitakrishnan	
<i>PA</i>	1G 6,518,796 B1	02/11/2003	Stan, et al.	
1H				
1I				
1J				
1K				

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
1L					
1M					
1N					
1O					
1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

<i>BS</i>	1Q	Paul Wiley, et al., "Building Robust, Reliable Nanometer ICs", EEdesign An EE Times Community, July 1998, pp. 1-8.
<i>BS</i>	1R	Synopsys Products & Solutions, "PathMill: Transistor-Level Static Timing Analysis", www.synopsys.com/products/analysis/pathmill_ds.html , March 8, 2000, pp. 1-3.
<i>BS</i>	1S	Synopsys PathMill--Datasheet, "PathMill DataSheet; Critical Path and Static timing Analysis", idec.kaist.ac.kr/CAD/epic/pathmill.html , Synopsys, Inc. October 13, 1997, pp. 1-4.

EXAMINER	DATE CONSIDERED
<i>BS</i>	<i>11/21/05</i>

PATENT APPLICATION

Sheet 2 of 2

FORM PTO-1449		ATTY. DOCKET NO. 200310257-1	APPLICATION NO. 10/635283	CONFIRMATION NO.
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		APPLICANT Thomas W. Chen	GROUP 0825	
(Use several sheets if necessary)		FILING DATE		

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
1A				
1B				
1C				
1D				
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1F				
1G				
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1L					
1M					
1N					
1O					
1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

<i>BB</i>	1Q	Synopsis Products & Solutions, "AMPS Datasheet Intelligent Design Optimization", www.synopsys.com/products/analysis/amps_ds.html , Synopsys, Inc. November 29, 1999, pp. 1-3
<i>BB</i>	1R	Tanay Karnik, et al., "Total Power Optimization By Simultaneous Dual-Vt Allocation and Device Sizing in High Performance Microprocessors", ACM, June 2002
<i>BB</i>	1S	Michel Crote, Philippe Hurat, "Better Cells for Better Designs Power and Performance Optimization of Cell-Based Designs with Transistor-level Cell Sizing, Chapter 9, pp. 1-16

EXAMINER

DATE CONSIDERED